

# SAMPIC: a readout chip for fast timing detectors

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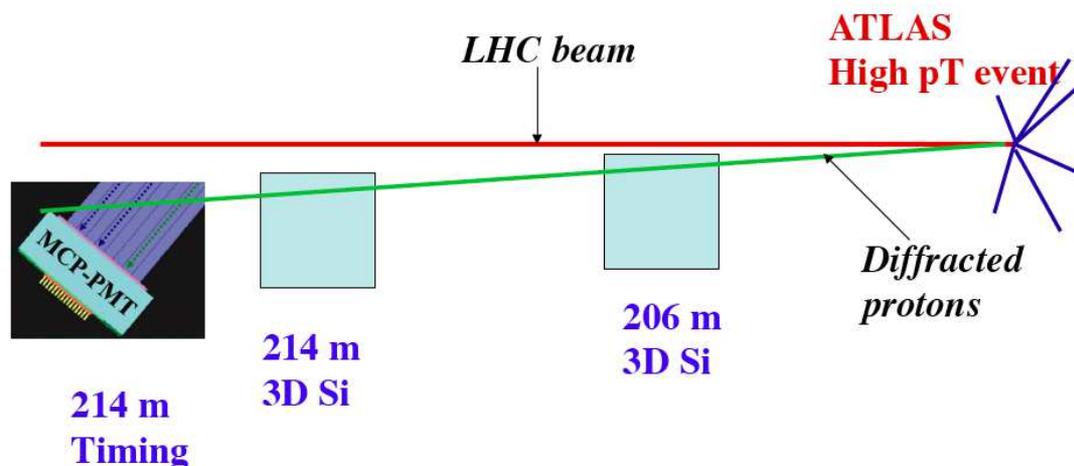
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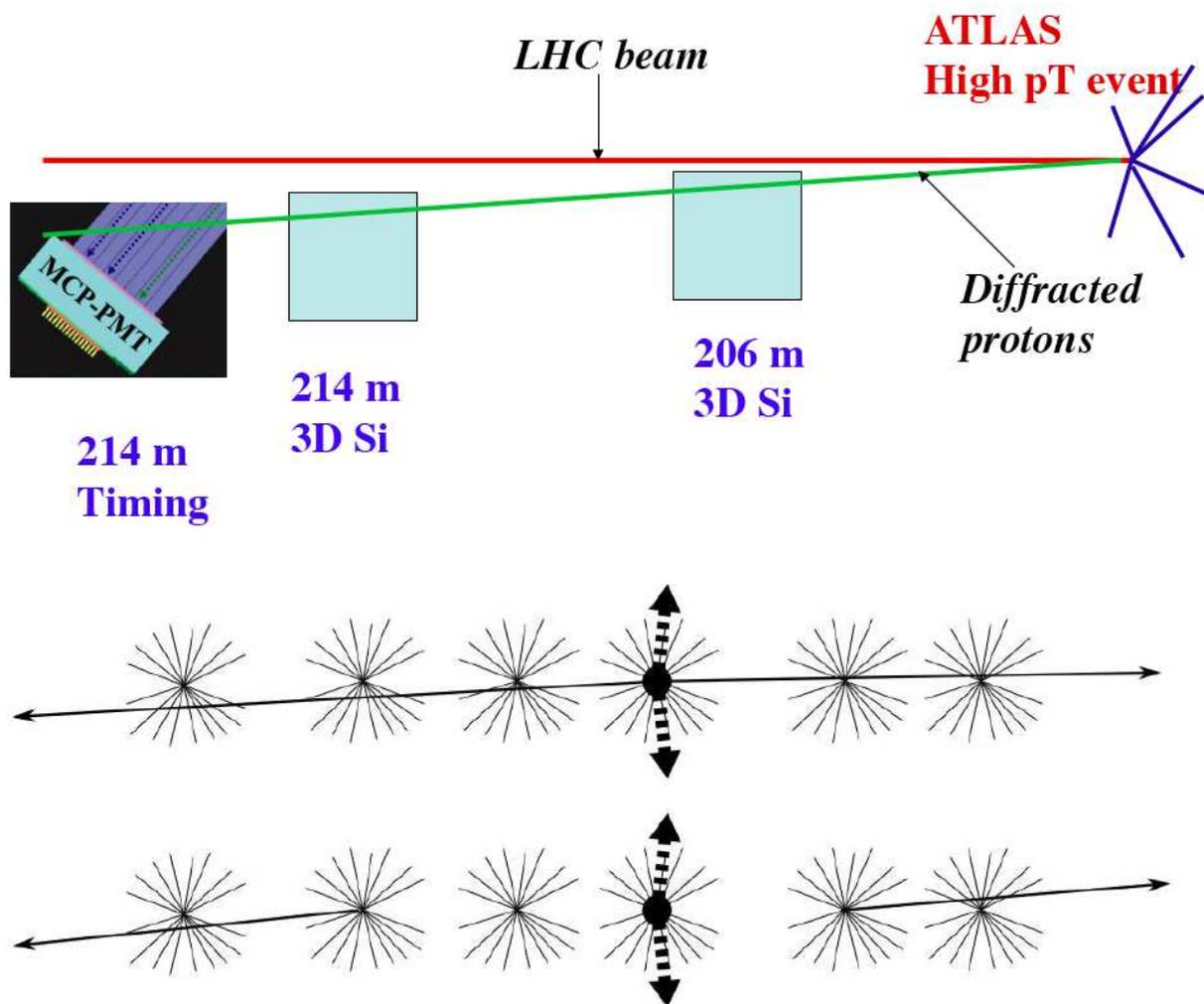
## Contents:

- What is SAMPIC?
- Possible applications of timing detectors
- SAMPIC tests: electronics and with Si/diamond/quartz detectors



## Introduction: Timing measurements in particle physics

- Proton time-of-flight measurements at the LHC in ATLAS (AFP), and CMS/TOTEM (CT-PPS):  $pp \rightarrow pXp$



- Determine if intact protons originate from main interaction in the events or from secondary ones (there are between 20-100 interactions per bunch crossing at the LHC)
- Ultimate goal of  $\sim 5-10$  ps resolution which means 1-2 mm in vertex position

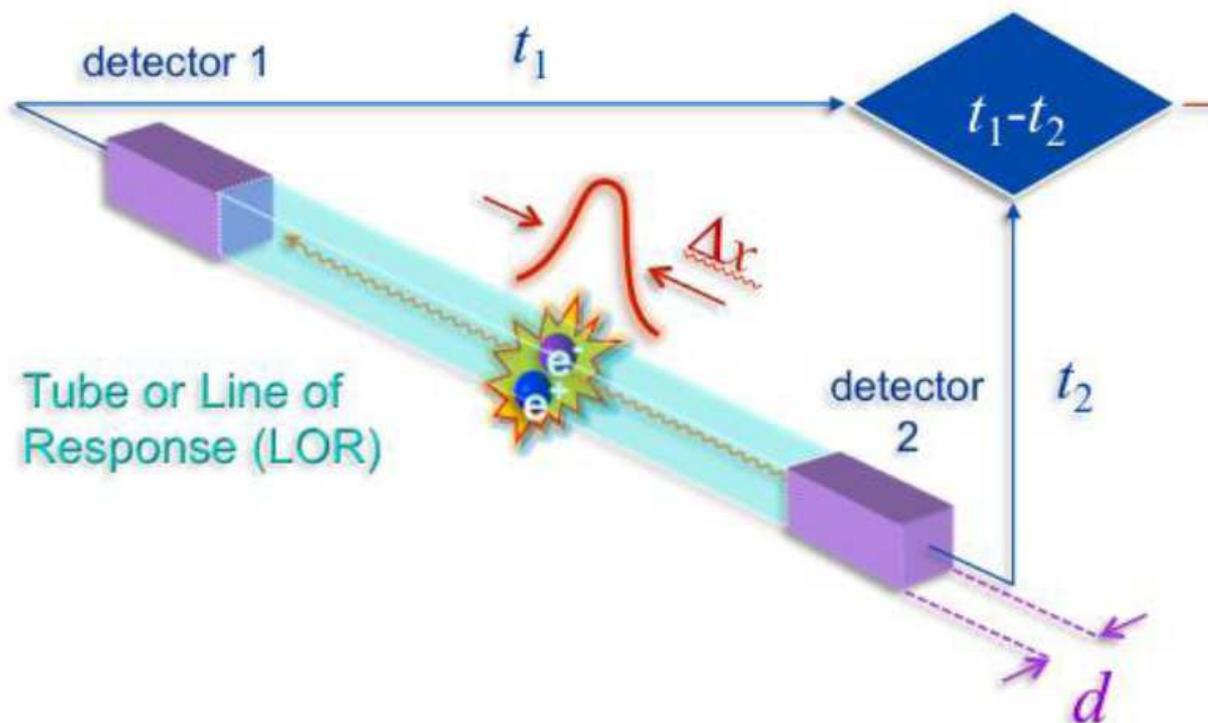
## Introduction: Timing measurements in medical imaging

- SAMPIC: working well, to be tested with detectors in beam tests
- Many applications especially in PET imaging (Manjit Dosanjh)

### The holy grail: “10-picosecond PET”

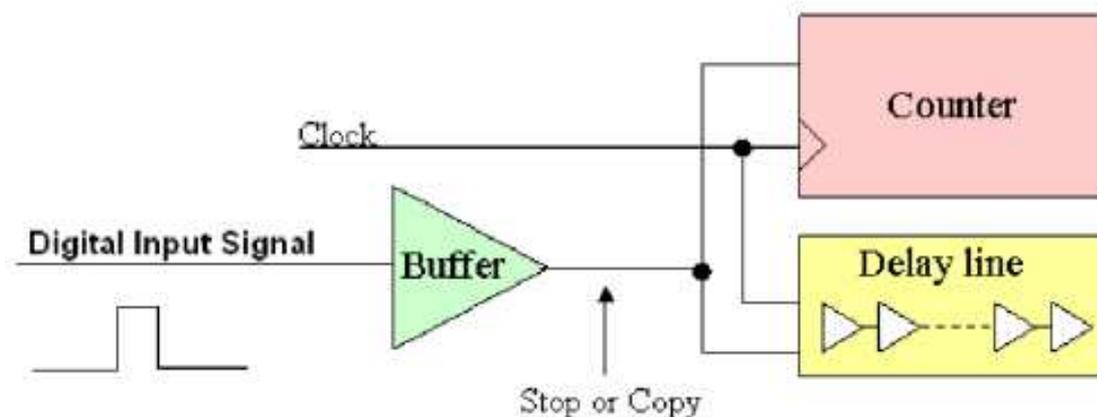
With a CRT less than  $\sim 20$  ps events can be localized directly:

- image reconstruction no longer necessary!
- only attenuation correction
- real-time image formation



## Introduction: why a new chip to get precise timing?

- Before SAMPIC, the most performant Time to Digit Converters (TDCs) use digital counters and Delay Line Loops (DLLs)

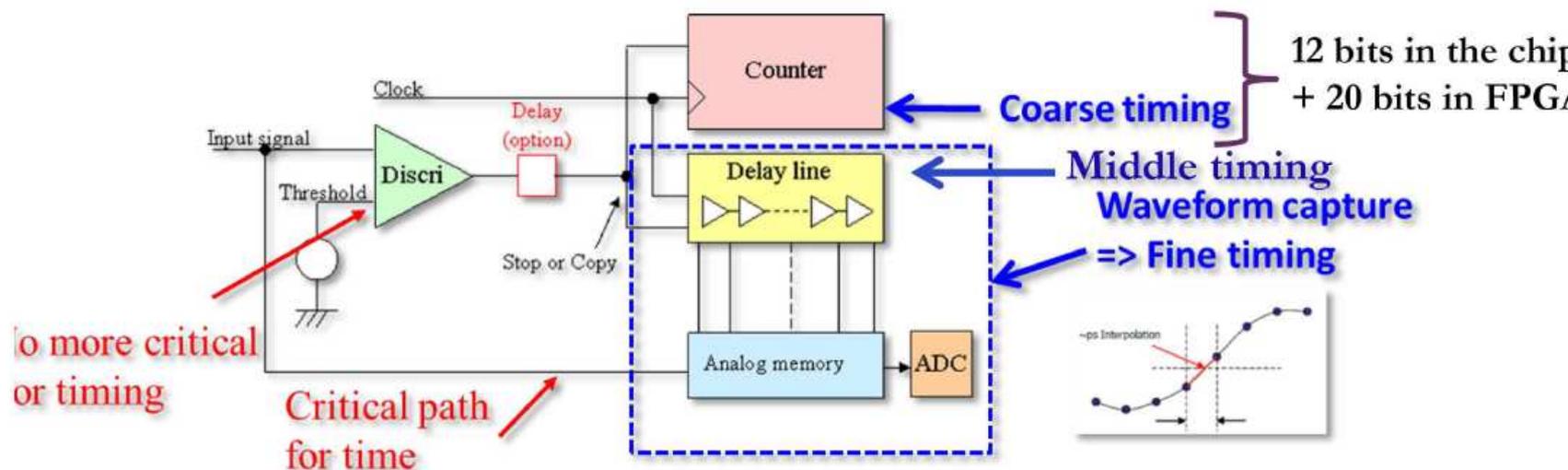


TDC Principle

- Timing resolution limited by the DLL step and with most advanced ASICs, we get  $\sim 20$  ps (new developments at CERN target 5 ps)
- A TDC needs a digital input signal: the analog input signal has to be transformed into a digital one with a discriminator which means that the timing resolution will be given by the quadratic sum of the discriminator and the TDC timing resolution

## SAMPIC: Waveform based TDC

- SAMPIC acquires the full waveform shape of a detector signal
  - Discriminator used only for triggering, not for timing: no jitter from it
  - All information is kept: possibility to use offline signal processing algorithms to improve timing resolution; can be used to obtain other signal characteristics as well (deposited charge...)
  - Important dead time per channel due to ADC conversion: about  $1 \mu\text{s}$ , to be reduced to about a factor 10 in the next version
- SAMPIC is cheap ( $\sim 10$  Euros per channel) (compared to a few 1000 Euros for previous technologies), which means that it can be used in large scale detectors such as PETs...



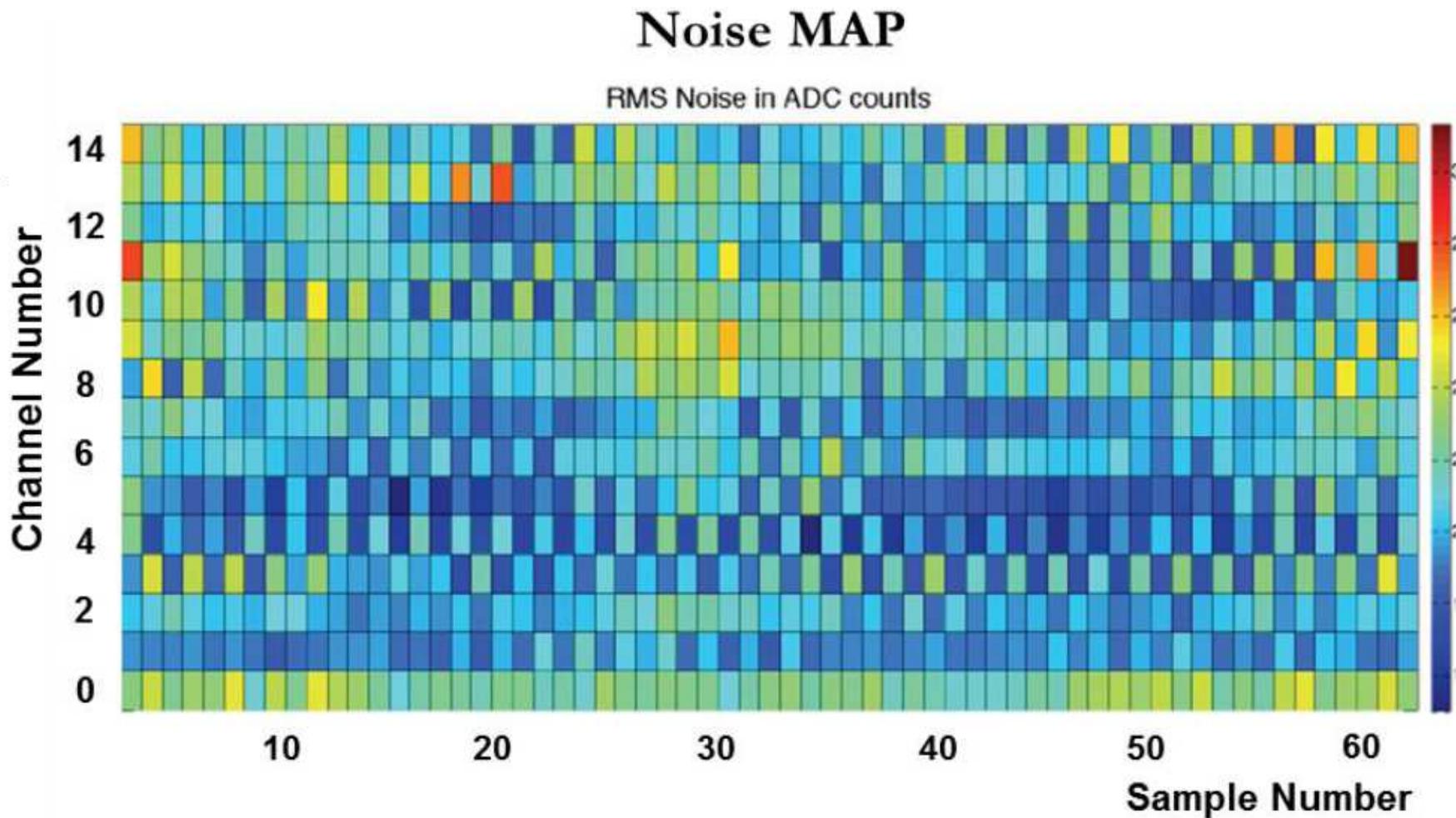
## SAMPIC and its acquisition board



- Mezzanine board can host two SAMPICS: 32-channel system
- MCX connectors and UBS-Ethernet-Optic fiber readout
- 5V voltage supply, 1 Amp.

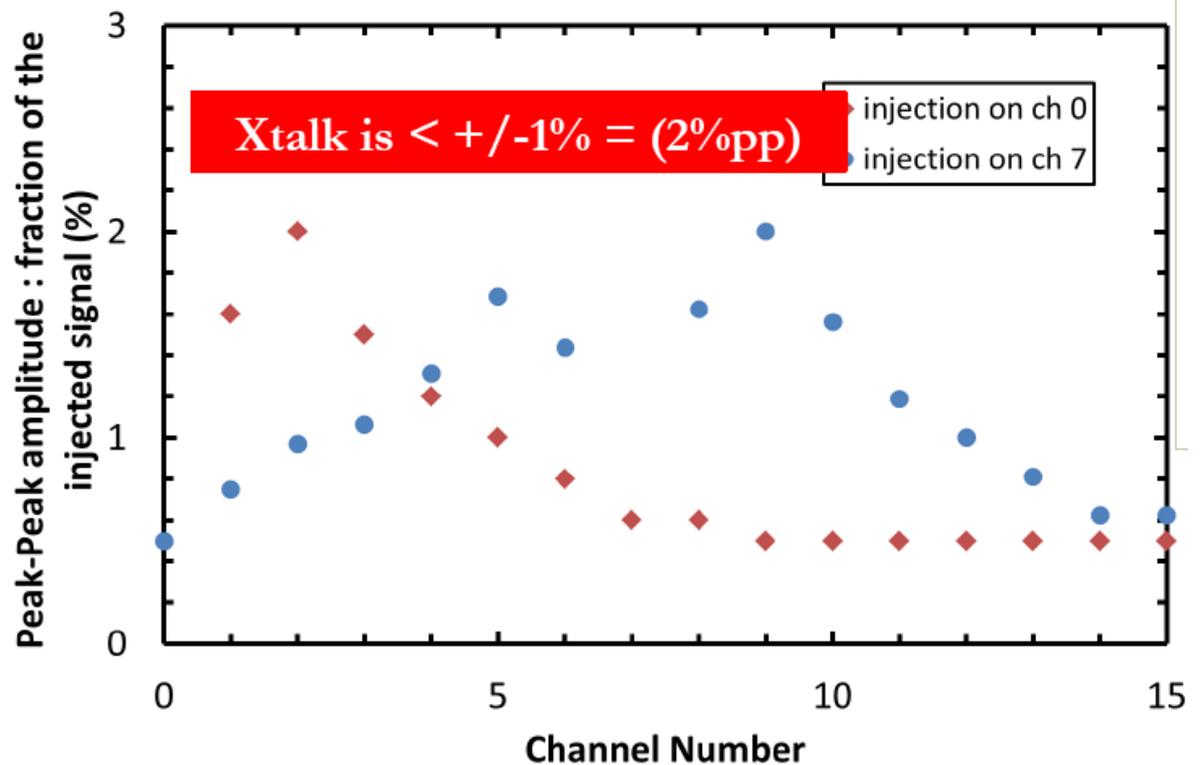
## SAMPIC noise

- Maximum signal size: 1V
- After corrections, average noise is 1 mV rms (noisiest cells are 1.5 mV rms), which means dynamic 10 bits rms



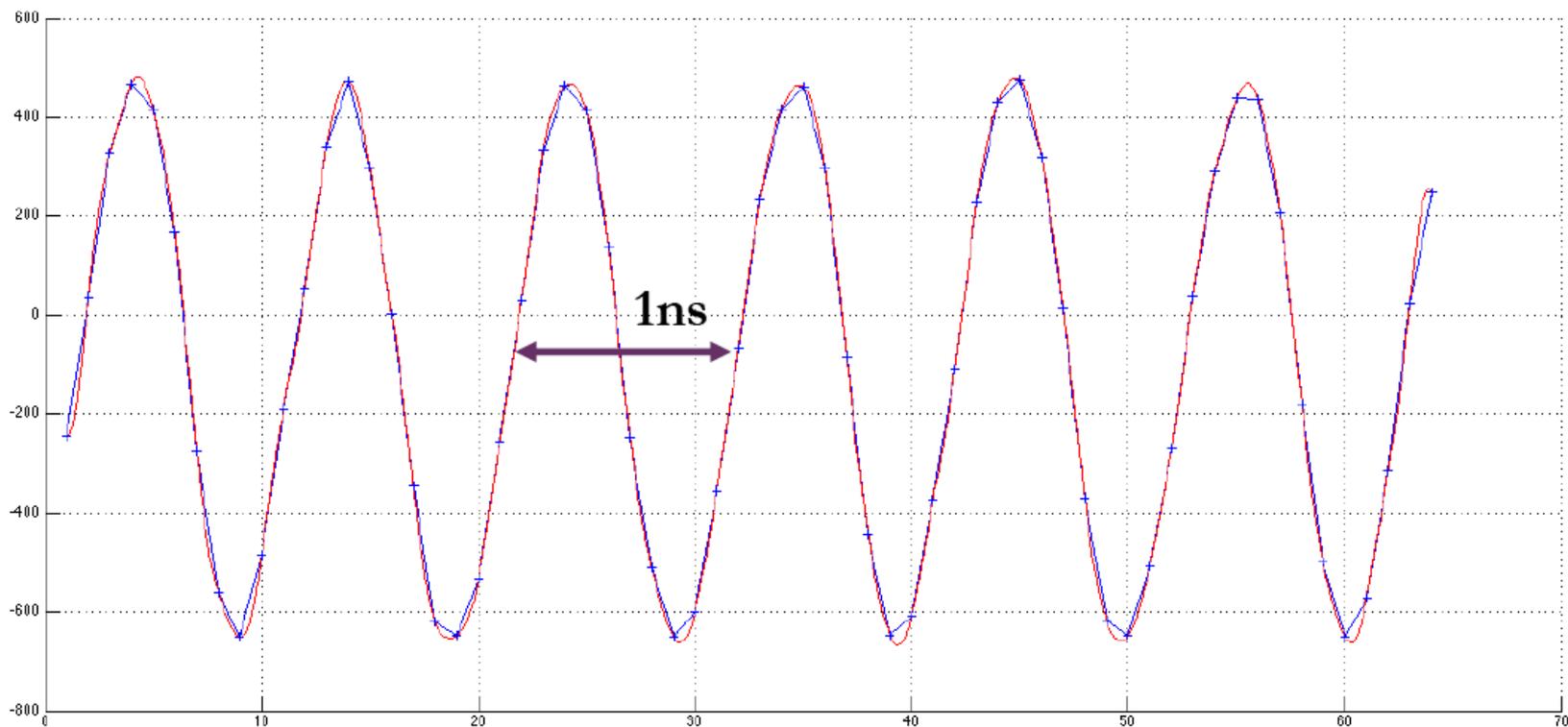
## SAMPIC cross talk measurement

- Signal of 800 mV, 300 ps rise time injected on channel 0 or 7 of SAMPIC
- Signal measured on other channel
- Cross talk is less than 1%



## Quality of sampling

- Sample speed from 3 to 8.2 Gigasample per second on 16 channels (up to 10 GSPS on 8 channels)
- **Already very good sampling quality:** example of sampling of a sinus without corrections at 10 GSPS

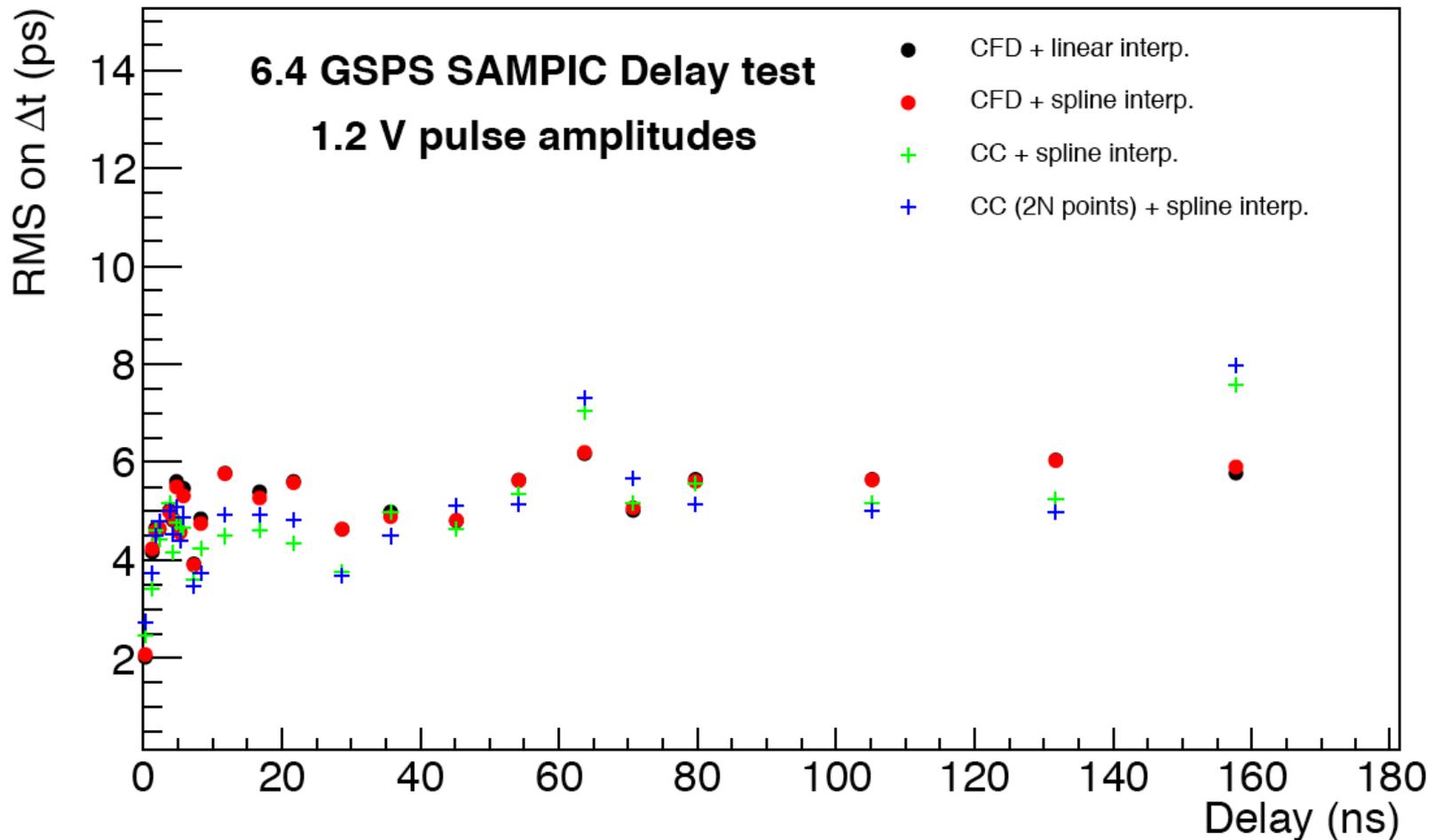


## Timing resolution vs delay



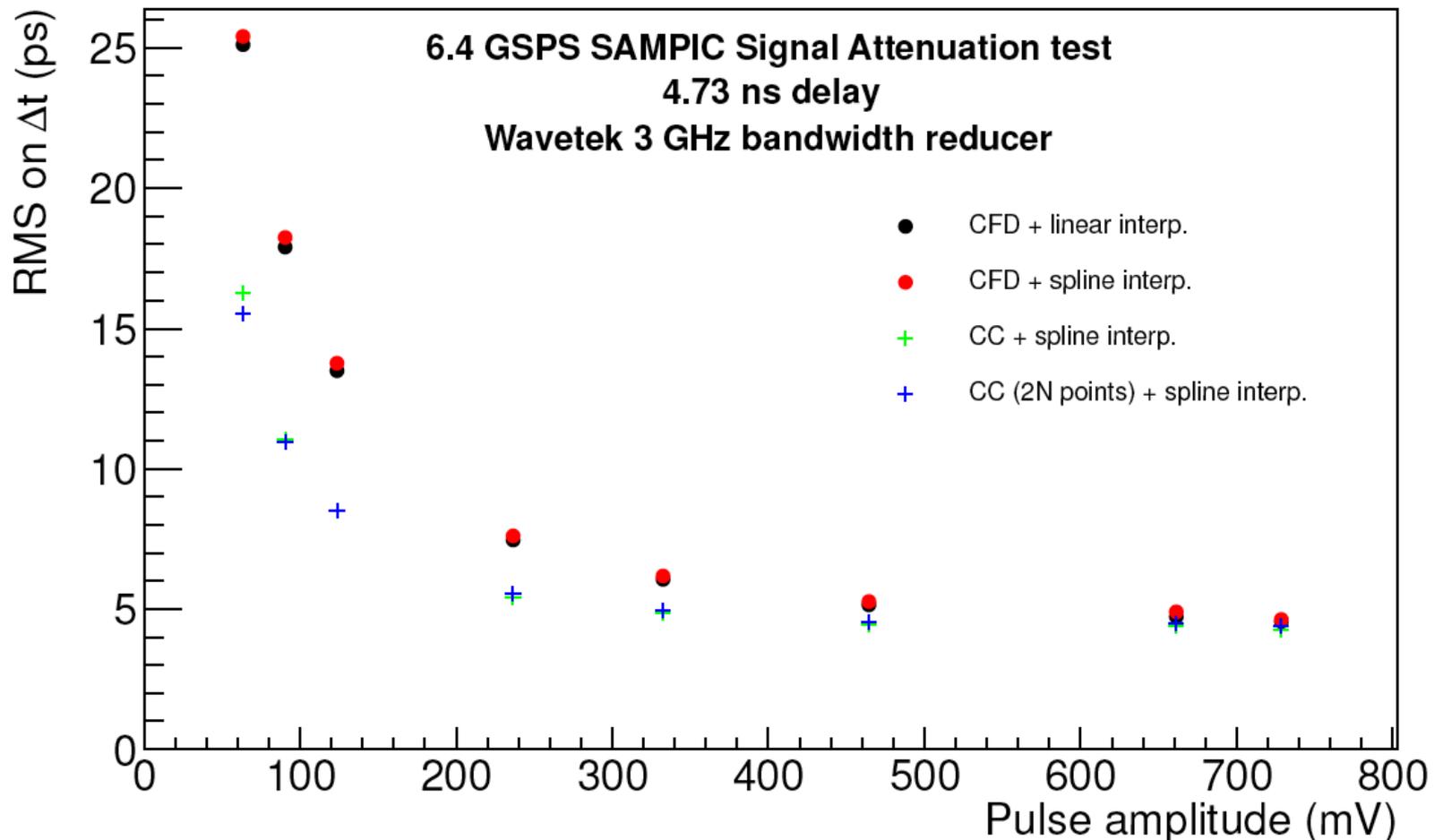
- Use two different channels of SAMPIC
- Send two times the same signal, one being delayed (delay box or longer cable)
- Measure the time difference and its RMS as a function of delay between 0 and  $\mu s$
- check SAMPIC stability as a function of delay

## Timing resolution vs delay



- Measure the RMS of the time difference between two pulses sent to SAMPIC vs delay using a pulse generator
- Different methods used: CFD (constant fraction discriminator), CC (cross correlation)
- Flat resolution of  $\sim 5$  ps vs delay: time resolution per channel of  $\sim 3$  ps

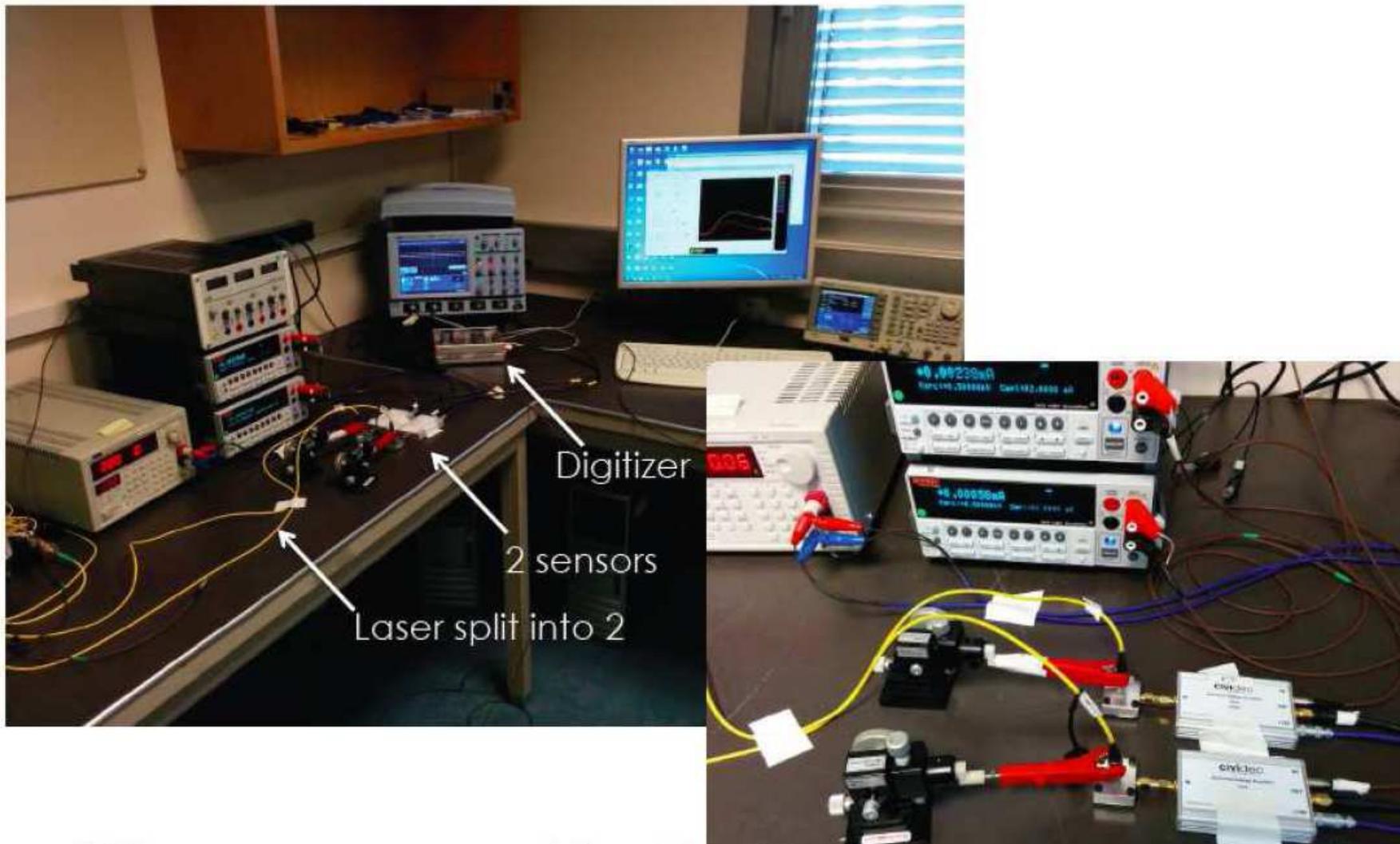
## Timing resolution vs signal amplitude



- Measure the RMS of the time difference between two pulses sent to SAMPIC vs the pulse amplitude using a pulse generator
- Different methods used: CFD (constant fraction discriminator), CC (cross correlation)
- Best time resolution if the signal is above 450 mV

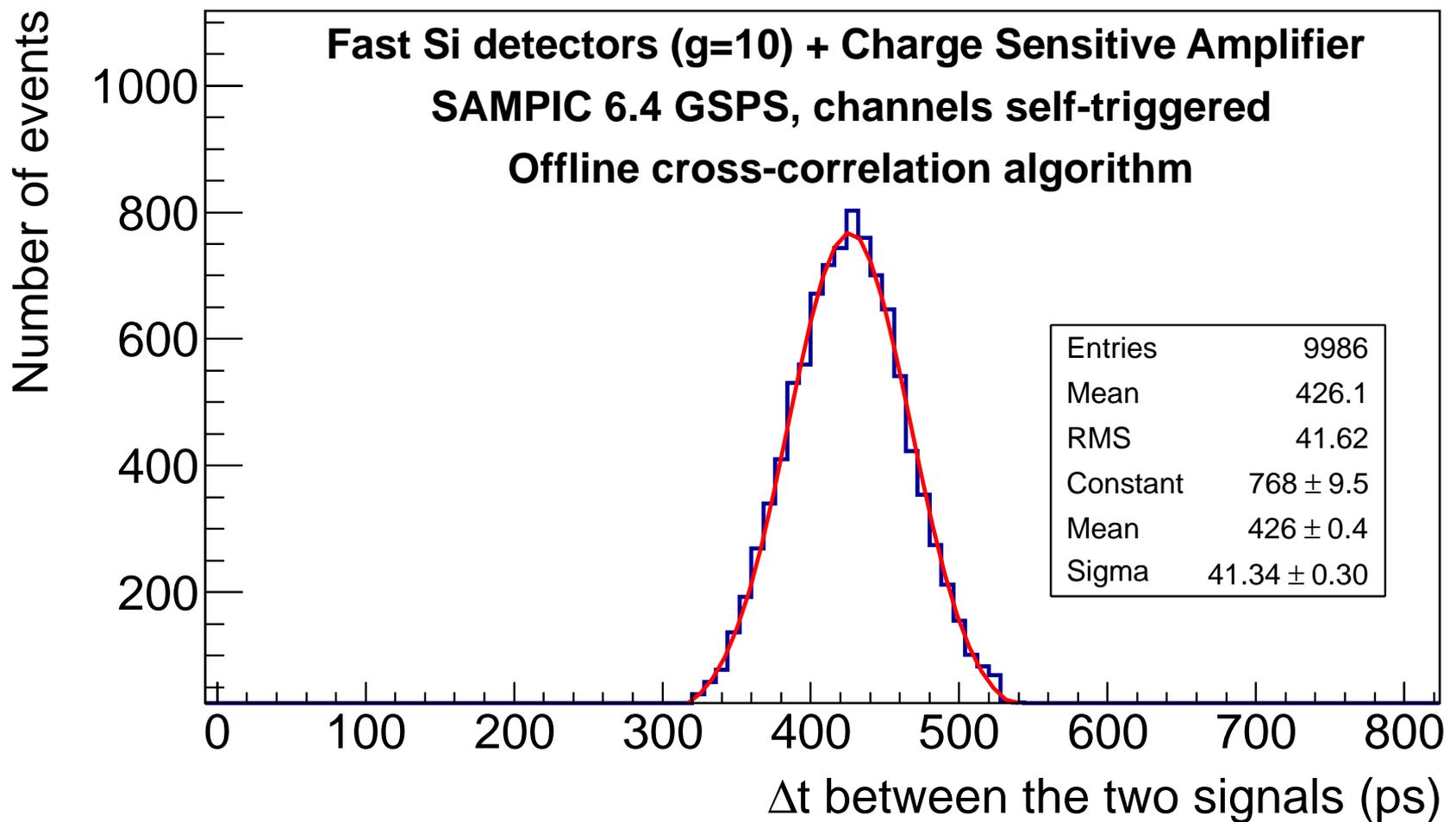
## Time resolution using Si detectors

- Test setup using a laser signal splitted in 2 read out by fast Si detector
- Time difference and RMS measured by SAMPIC



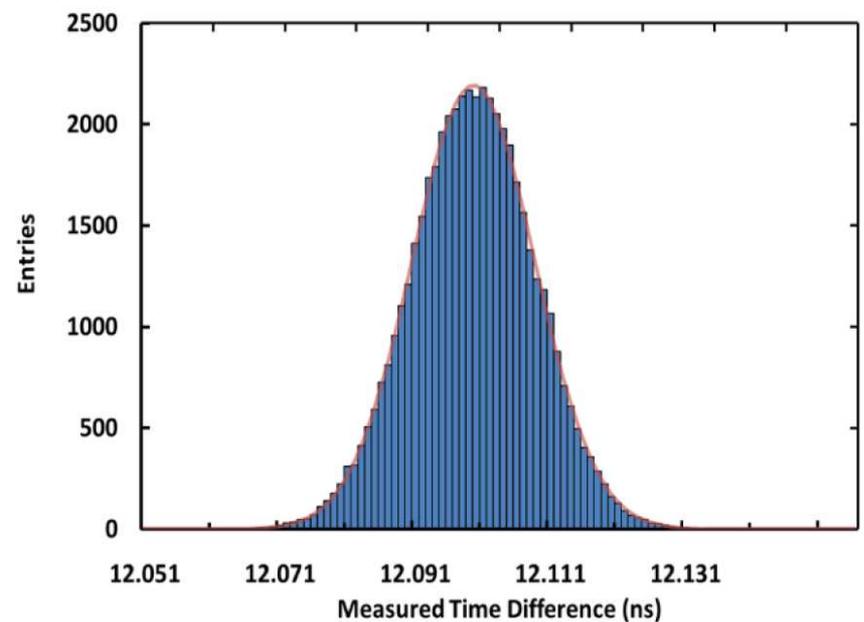
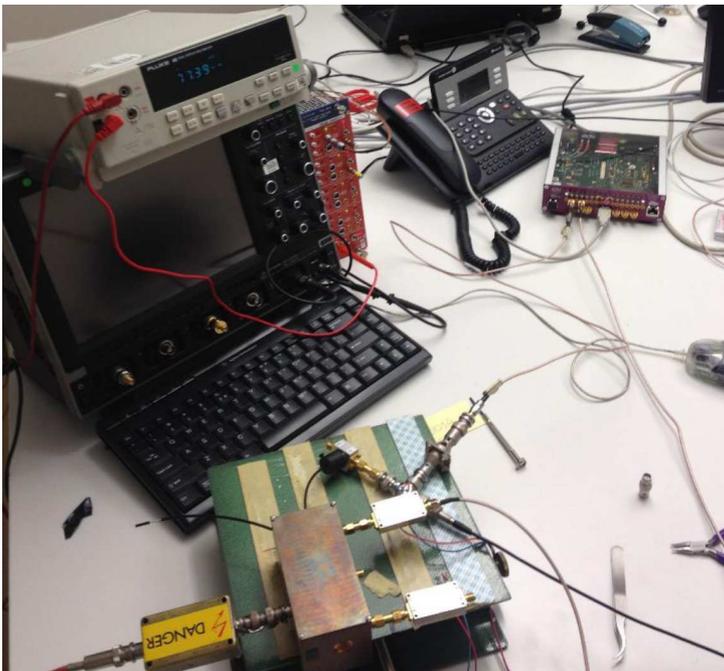
## Time resolution using Si detectors

- Time resolution using sampic and fast Si detectors (Nicolo): measure the time difference between two channels
- Time resolution: (dominated by detector):  $\sim 30$  ps
- Results in beam tests for diamond detectors: resolution of  $\sim 80$ -90 ps because of the slower rise time of the signal (4.5 ns)



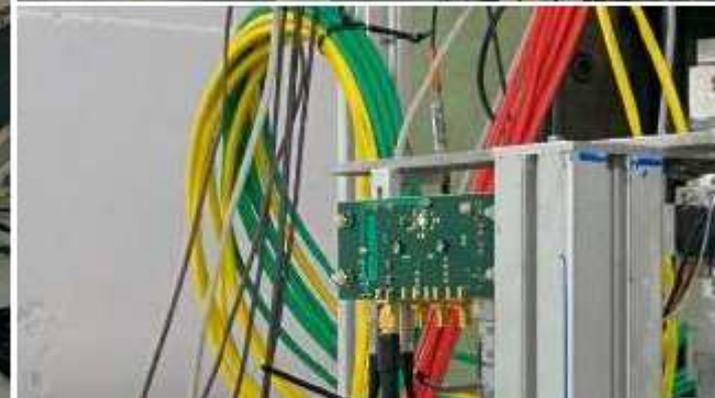
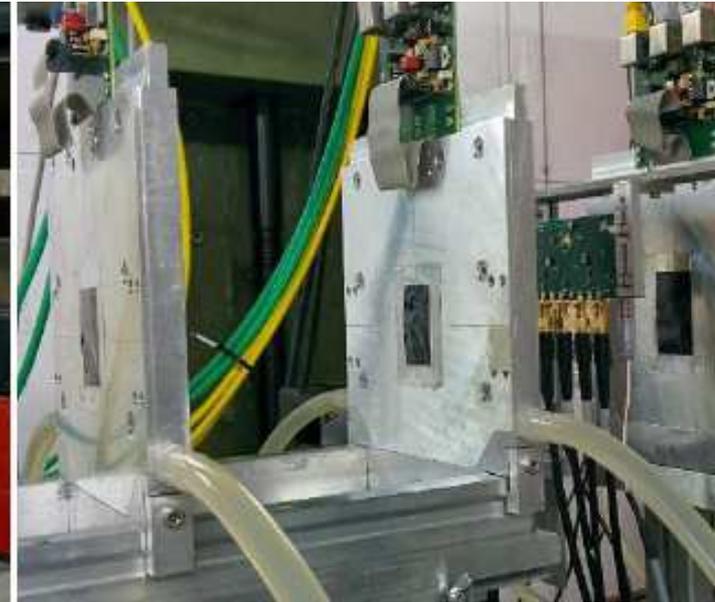
## Time resolution using fast mesh APD detectors

- Time resolution using sampic and fast mesh APD detectors: measure the time difference between two channels (one is the pulser and the other one the APD mesh output (Sebastian))
- Time resolution: (dominated by detector):  $\sim 10$  ps



## Beam tests in TOTEM using diamond detectors (I)

- Beam tests performed at DESY and CERN by TOTEM using diamonds detectors and SAMPIC



## Beam tests in TOTEM using diamond detectors (II)

- Beam tests performed at DESY and CERN by TOTEM using diamonds detectors and SAMPIC



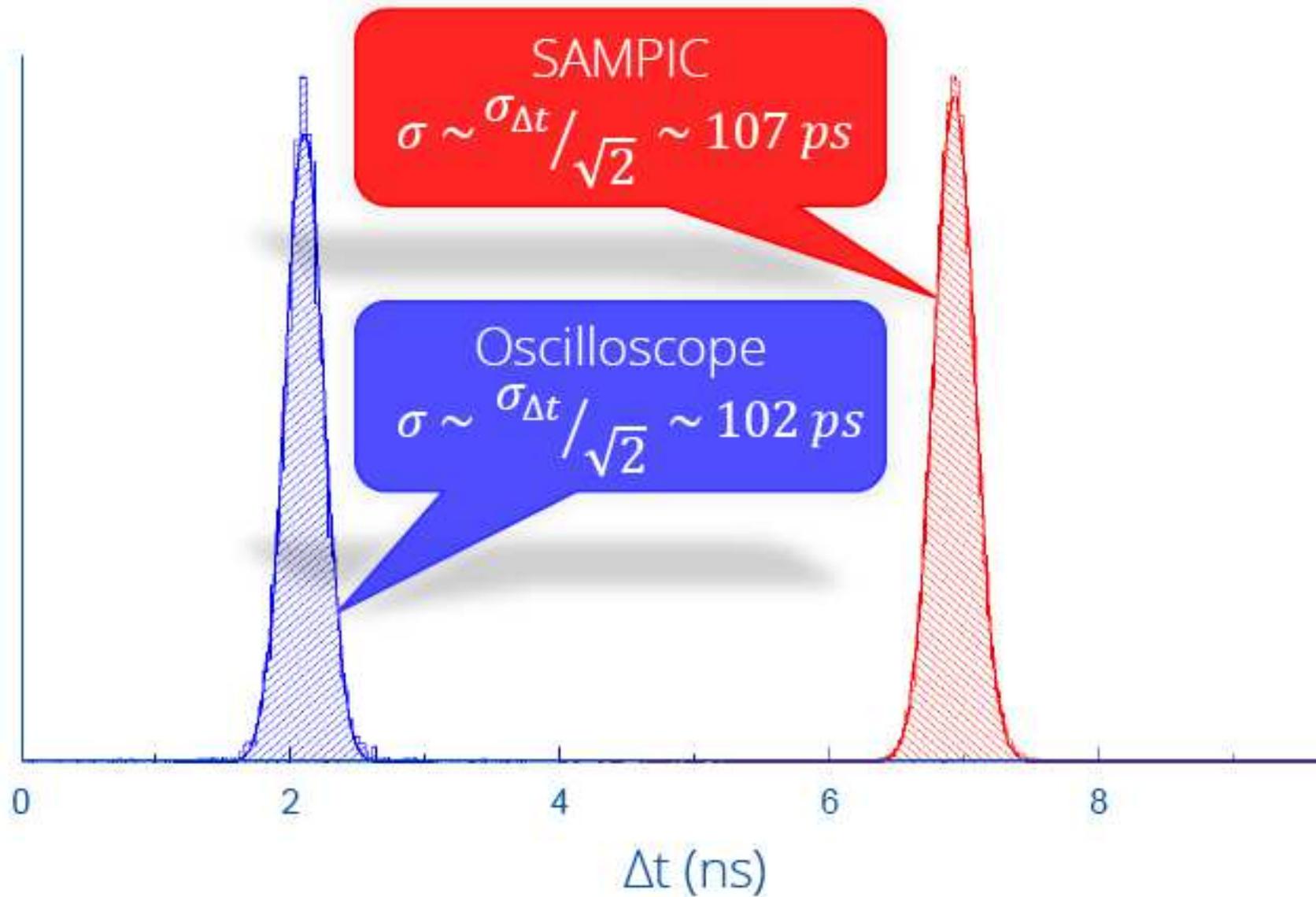
Agilent DSO 9254A  
2.5 GHz bandwidth  
10 Gs/s  
8 bit  
> 1000 samples  
4 channels  
Maximum rate ~100 Hz



SAMPIC  
2.5 GHz bandwidth  
10 Gs/s (used at 6.4 Gs/s)  
11 bit  
64 samples  
16 channels  
Maximum rate ~500 kHz

## Beam tests in TOTEM using diamond detectors (III)

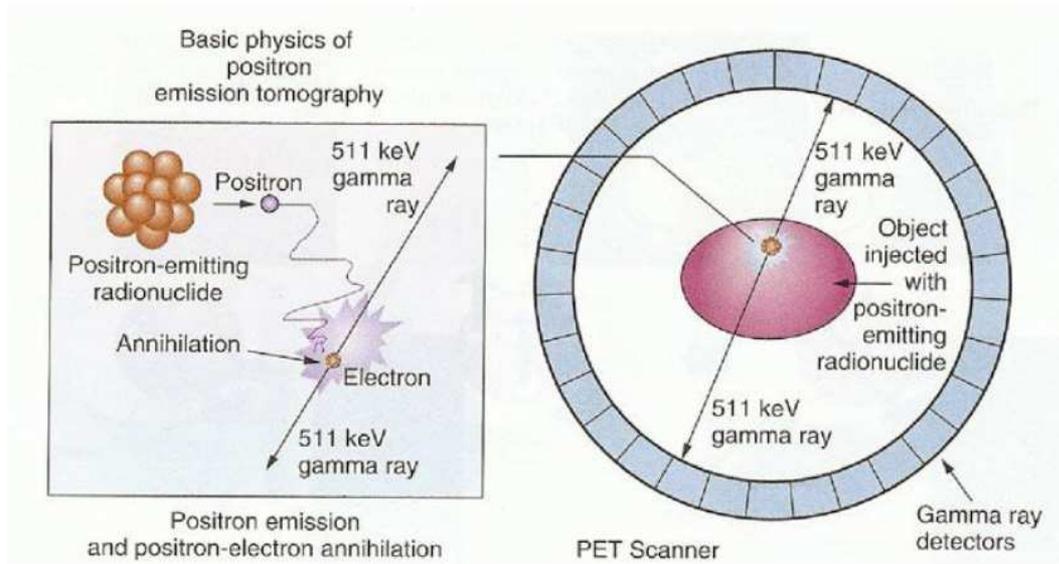
- Measure the resolution on the time difference between two channels



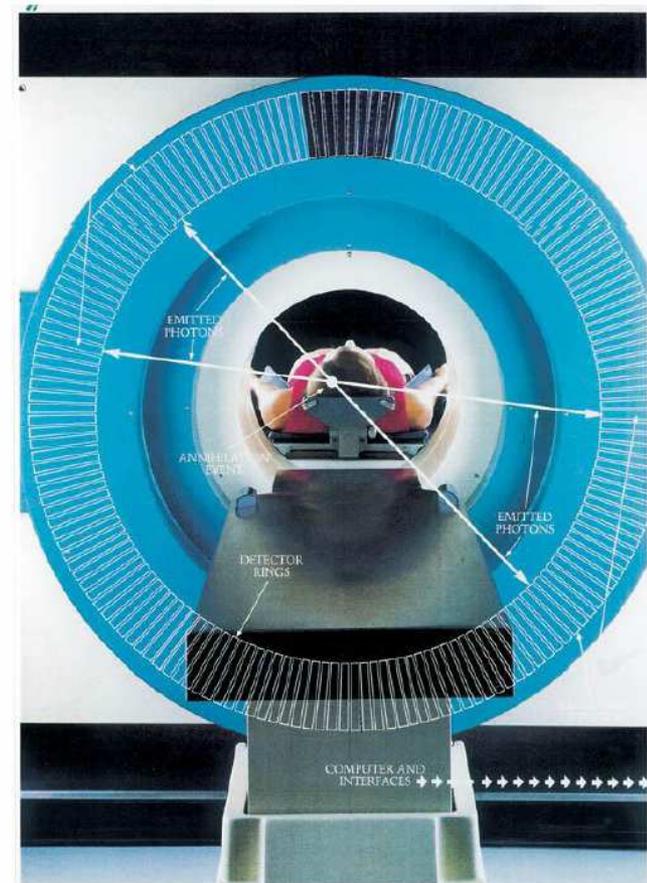
## SAMPIC0 summary

		Unit
Technology	AMS CMOS 0.18 $\mu$ m	
Number of channels	16	
Power consumption	180 (1.8V supply)	mW
Discriminator noise	2	mV rms
SCA depth	64	Cells
Sampling Speed	<3-8.4 (10.2 for 8 channels only)	GSPS
Bandwidth	1.6	GHz
Range (Unipolar)	1	V
ADC resolution	8 to 11 (trade-off time/resolution)	bit
SCA noise	<1.3	mV rms
Dynamic range	9.6	Bit rms
Conversion time	0.2-1.6 (8bit-11bit)	$\mu$ s
Readout time (can be probably be /2 )	25 + 6.2/sample	ns
Time precision before correction	15	ps rms
Time precision after timing INL correction	< 5	ps rms

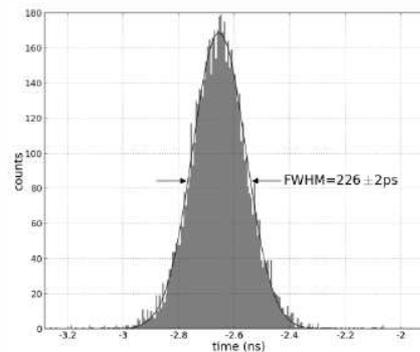
## The future: Application: Timing measurements in Positron Emission Tomography



Positron emission and positron-electron annihilation



Coincidence Resolving Time:



- The Holy grail: 10 picosecond PET (3 mm resolution)
- What seemed to be a dream a few years ago seems now to be closer to reality
- Other possible application in drone technology: fast decision taking and distance measurement using laser

## Conclusion

- A self-triggered chip demonstrator has been designed and characterised: 1.6 GHz bandwidth, up to 10 GSPS, low noise (trigger and acquisition), <5 ps rms timing resolution
- **Chip is usable for tests with detectors:** tests started with quartz, diamond, Si detector together with ATLAS/CMS/Totem; intrinsic time resolution of  $\sim 3$  ps
- Work going on on DAQ system optimisation (firmware and software), second prototype including dead time improvement (ping-pong)
- **Laser tests with Si detectors, Beam tests in common with CMS/Totem with diamond detectors**
- **SAMPIC can be used for many timing applications:** PETs, cosmic applications... in detectors including many channels due to the low cost per channel

